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10771553_CLS Most Frequently Occurring Classifications of Patents Returned From A Search of 10814207 on May 27, 2004

Origin 17	inal Classifications 250/288 204/452 210/198.2 204/453 216/2 250/281 204/451 204/603 210/656 216/79
Cross 20 14 14 10 9 8 7 7 7 5 5 4 4 4 3 3 3 3 3 3 2 2 2 2 2 2 2 2 2 2 2	

2 436/177

Page 1

10771553 CLS

- 2 436/86
- 2 436/87
- 2 436/89
- 2 436/91
- 2 436/93
- 2 436/94
- 2 438/756

Combined Classifications

- 37 250/288
- 17 250/281
- 14 250/282
- 12 210/198.2
- 10 204/603
- 10 210/748
- 9 204/452
- 9 210/243
- 9 210/656
- 8 204/601
- 7 204/600
- 5 216/79
- 5 250/423R
- 5 438/743
- 4 204/451
- 4 204/453
- 4 204/604
- 4 438/723
- 3 216/2
- 3 216/67
- 3 250/292
- 3 436/161
- 3 436/173
- 3 438/734
- 3 438/736
- 3 438/942
- 2 204/450
- 2 216/39
- 2 216/47
- 2 216/80
- 2 250/289
- 2 422/70
- 2 436/174
- 2 436/177
- 2 436/86
- 2 436/87
- 2 436/89
- 2 436/91
- 2 436/93

2 436/94 2 438/756

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Page 3

10771553 CLSTITLES

Titles of Most Frequently Occurring Classifications of Patents Returne

From A Search of 10814207 on May 27, 2004

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(17 OR, 20 XR)
 37
    250/288
          Class
                  250 : RADIANT ENERGY
                        IONIC SEPARATION OR ANALYSIS
          250/281
          250/288
                        .With sample supply means
                   (3 OR, 14 XR)
 17
    250/281
          Class
                  250 : RADIANT ENERGY
                        IONIC SEPARATION OR ANALYSIS
          250/281
 14 250/282
                   (0 OR, 14 XR)
                  250 : RADIANT ENERGY
          Class
          250/281
                        IONIC SEPARATION OR ANALYSIS
          250/282
                        .Methods
 12 210/198.2
                   (5 OR, 7 XR)
                  210 : LIQUID PURIFICATION OR SEPARATION
                        WITH MEANS TO ADD TREATING MATERIAL
          210/198.1
          210/198.2
                        .Chromatography
 10 204/603
                   (2 OR, 8 XR)
                  204 : CHEMISTRY: ELECTRICAL AND WAVE ENERGY
          Class
          204/193
                        APPARATUS
          204/600
                        .Electrophoretic or electro-osmotic apparatus
          204/601
                        .. Capillary electrophoresis type
          204/603
                        ...With detailed detection system (e.g.,
                           including a light source and a camera, etc.
 10 210/748
                   (0 OR, 10 XR)
                  210 : LIOUID PURIFICATION OR SEPARATION
          Class
          210/600
                        PROCESSES
          210/748
                        .Utilizing electrical or wave energy (directly
                           applied to liquid or material being treated
    204/452
                   (5 OR, 4 XR)
                  204: CHEMISTRY: ELECTRICAL AND WAVE ENERGY
          Class
                        .Electrophoresis or electro-osmosis processes
          204/450
                             and electrolyte compositions therefor whe
n not provided for
                             elsewhere
          204/451
                        .. Capillary electrophoresis
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10771553 CLSTITLES

	204/452		With	detailed d	letecti	on
9	210/243	(0	OR, 9 XR)			
	Class	210	: LIQUID	PURIFICATI	ON OR	SEI

Class 210: LIQUID PURIFICATION OR SEPARATION
210/243 ELECTRICAL INSULATING OR ELECTRICITY
DISCHARGING

9 210/656 (2 OR, 7 XR) Class 210: LIQUID PURIFICATION OR SEPARATION 210/600 PROCESSES 210/656 .Chromatography

8 204/601 (1 OR, 7 XR)
Class 204: CHEMISTRY: ELECTRICAL AND WAVE ENERGY
204/193 APPARATUS
204/600 .Electrophoretic or electro-osmotic apparatus

204/601 ..Capillary electrophoresis type

7 204/600 (0 OR, 7 XR)
Class 204: CHEMISTRY: ELECTRICAL AND WAVE ENERGY
204/193 APPARATUS
204/600 .Electrophoretic or electro-osmotic apparatus

5 216/79 (2 OR, 3 XR)
Class 216: ETCHING A SUBSTRATE: PROCESSES
216/58 GAS PHASE ETCHING OF SUBSTRATE
216/74 .Etching inorganic substrate
216/79 .Etching silicon containing substrate

5 250/423R (0 OR, 5 XR) Class 250: RADIANT ENERGY

250/423R ION GENERATION
5 438/743 (0 OR, 5 XR)

438/689 CHEMICAL ETCHING
438/706 .Vapor phase etching (i.e., dry etching)
438/735 ..Differential etching of semiconductor
substrate
438/737 ...Substrate possessing multiple layers

Class 438: SEMICONDUCTOR DEVICE MANUFACTURING: PROCESS

438/743Silicon oxide or glass
4/451 (2 OR, 2 XR)

4 204/451 (2 OR, 2 XR)
Class 204: CHEMISTRY: ELECTRICAL AND WAVE ENERGY
204/450 .Electrophoresis or electro-osmosis processes

10771553 CLSTITLES and electrolyte compositions therefor when not provided for elsewhere 204/451 .. Capillary electrophoresis (3 OR, 1 XR) 204/453 204 : CHEMISTRY: ELECTRICAL AND WAVE ENERGY 204/450 .Electrophoresis or electro-osmosis processes and electrolyte compositions therefor whe n not provided for elsewhere 204/451 .. Capillary electrophoresis ...With injection 204/453 204/604 (0 OR, 4 XR) 204 : CHEMISTRY: ELECTRICAL AND WAVE ENERGY Class 204/193 APPARATUS 204/600 .Electrophoretic or electro-osmotic apparatus 204/601 .. Capillary electrophoresis type 204/604 ...With injector 438/723 (0 OR, 4 XR)438 : SEMICONDUCTOR DEVICE MANUFACTURING: PROCESS Class 438/689 CHEMICAL ETCHING 438/706 .Vapor phase etching (i.e., dry etching) .. Utilizing electromagnetic or wave energy 438/707 438/710 ... By creating electric field (e.g., plasma, glow discharge, etc.) 438/723Silicon oxide or glass 3 216/2 (3 OR, 0 XR) 216 : ETCHING A SUBSTRATE: Class PROCESSES ETCHING OF SEMICONDUCTOR MATERIAL TO PRODUCE A 216/2 Ν ARTICLE HAVING A NONELECTRICAL FUNCTION 3 216/67 (0 OR, 3 XR) 216 : ETCHING A SUBSTRATE: **PROCESSES** Class GAS PHASE ETCHING OF SUBSTRATE 216/58 216/63 .Application of energy to the gaseous etchant or to the substrate being etched 216/67 .. Using plasma 250/292 (0 OR, 3 XR) Class 250 : RADIANT ENERGY

IONIC SEPARATION OR ANALYSIS

250/281

			40004550	
	250/290		10771553_CLSTITLES .Cyclically varying ion selecting field means	
	250/292		Laterally resonant ion path	
3	436/161 Class		OR, 3 XR) : CHEMISTRY: ANALYTICAL AND IMMUNOLOGICAL TESTING	
	436/161			
3		-	OR, 2 XR) : CHEMISTRY: ANALYTICAL AND IMMUNOLOGICAL TESTING	
	436/173			
CTRO	DMETRY			
3			OR, 3 XR) : SEMICONDUCTOR DEVICE MANUFACTURING: PROCESS	
	438/689 438/706 438/734		CHEMICAL ETCHING .Vapor phase etching (i.e., dry etching)Sequential etching steps on a single layer	
3			OR, 3 XR) : SEMICONDUCTOR DEVICE MANUFACTURING: PROCESS	
	438/689 438/706 438/735		CHEMICAL ETCHING .Vapor phase etching (i.e., dry etching)Differential etching of semiconductor substrate	
	438/736		Utilizing multilayered mask	
3	438/942 Class		OR, 3 XR) : SEMICONDUCTOR DEVICE MANUFACTURING: PROCESS	
	438/942		MASKING	
2	204/450 Class 204/450		OR, 2 XR) : CHEMISTRY: ELECTRICAL AND WAVE ENERGY .Electrophoresis or electro-osmosis processes and electrolyte compositions therefor when	
not provided for				
			elsewhere	
2	216/39 Class 216/39		OR, 2 XR) : ETCHING A SUBSTRATE: PROCESSES FORMING GROOVE OR HOLE IN A SUBSTRATE WHICH IS SUBSEQUENTLY FILLED OR COATED	

10771553_CLSTITLES

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T	2	(Class	216	OR, 2 XR) : ETCHING A SUBSTRATE: PROCESSES MASKING OF A SUBSTRATE USING MATERIAL RESISTAN
			216/47		TO AN ETCHANT (I.E., ETCH RESIST) .Mask is multilayer resist
	2			216	OR, 2 XR) : ETCHING A SUBSTRATE: PROCESSES GAS PHASE ETCHING OF SUBSTRATE .Etching inorganic substrate .Etching silicon containing substrateSilicon containing substrate is glass
	2		Class	250	OR, 1 XR) : RADIANT ENERGY IONIC SEPARATION OR ANALYSIS .With evacuation or sealing means
E	2	(Class	422	OR, 2 XR) : CHEMICAL APPARATUS AND PROCESS DISINFECTING, DEODORIZING, PRESERVING, OR STERILIZING ANALYZER, STRUCTURED INDICATOR, OR MANIPULATIV
			422/68.1 422/69 422/70		LABORATORY DEVICE .Means for analyzing liquid or solid sampleSorption testingLiquid chromatography
	2	(Class	436	OR, 2 XR) : CHEMISTRY: ANALYTICAL AND IMMUNOLOGICAL TESTING INCLUDING SAMPLE PREPARATION
	2			436	
filtering,			,		centrifuging, etc.)

Page 5

10771553_CLSTITLES

2		436	OR, 2 XR) : CHEMISTRY: ANALYTICAL AND IMMUNOLOGICAL TESTING PEPTIDE, PROTEIN OR AMINO ACID .Glycoproteins (e.g., hormone, etc.)
2	436/89 Class 436/86 436/89	436	OR, 2 XR) : CHEMISTRY: ANALYTICAL AND IMMUNOLOGICAL TESTING PEPTIDE, PROTEIN OR AMINO ACID .Amino acid or sequencing procedure
2		436	OR, 2 XR) : CHEMISTRY: ANALYTICAL AND IMMUNOLOGICAL TESTING HETEROCYCLIC CARBON COMPOUND (I.E., O, S, N, Se, Te, AS ONLY RING HETERO ATOM)
2	436/93 Class 436/91 436/93	436	OR, 2 XR) : CHEMISTRY: ANALYTICAL AND IMMUNOLOGICAL TESTING HETEROCYCLIC CARBON COMPOUND (I.E., O, S, N, Se, Te, AS ONLY RING HETERO ATOM) .Hetero-O (e.g., ascorbic acid, etc.)
2	436/91 436/93	436	: CHEMISTRY: ANALYTICAL AND IMMUNOLOGICAL TESTING HETEROCYCLIC CARBON COMPOUND (I.E., O, S, N, Se, Te, AS ONLY RING HETERO ATOM) .Hetero-O (e.g., ascorbic acid, etc.)
2	438/756 Class 438/689 438/745 438/756	438	OR, 2 XR) : SEMICONDUCTOR DEVICE MANUFACTURING: PROCESS CHEMICAL ETCHING .Liquid phase etchingSilicon oxide